

PATENT ABSTRACTS OF JAPAN



(11)Publication number : 10-197598

(43)Date of publication of application : 31.07.1998

(51)Int.Cl.

G01R 31/26
H01R 23/02
H01R 33/76

(21)Application number : 09-005700

(71)Applicant : JSR CORP

(22)Date of filing : 16.01.1997

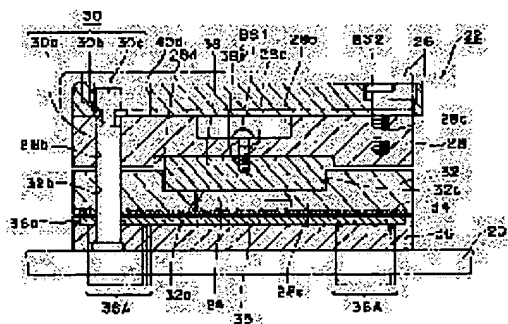
(72)Inventor : INOUE KAZUO

(54) INSPECTION JIG

(57)Abstract:

PROBLEM TO BE SOLVED: To provide an inspection jig which can apply a pressure within an allowable range evenly to the terminals of an installed semiconductor device without applying undesirable shearing force to the contacting surfaces between the terminals of the semiconductor device and terminals on a base board.

SOLUTION: A supporting part 28 having a pusher 38 is borne and guided by a shaft 30, and a sliding member 26 arranged on the oversurface of the supporting part 28 is pressed to the oversurface of a semiconductor device 24 to cause the bottom surface of the pusher 38 to contact with the bottom surface of a recess 32c, and then is slid in one direction toward the oversurface of the supporting part 28. Thereby a detent piece (40c) on the sliding member 26 is engaged by the coupling part 30b of the shaft 30, and the pressed condition by the pusher 38 is kept.



LEGAL STATUS

[Date of request for examination]

24.12.2003

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than

the examiner's decision of rejection or
application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's
decision of rejection]

[Date of requesting appeal against examiner's
decision of rejection]

[Date of extinction of right]

Copyright (C); 1998,2003 Japan Patent Office